

New Space Electronics®

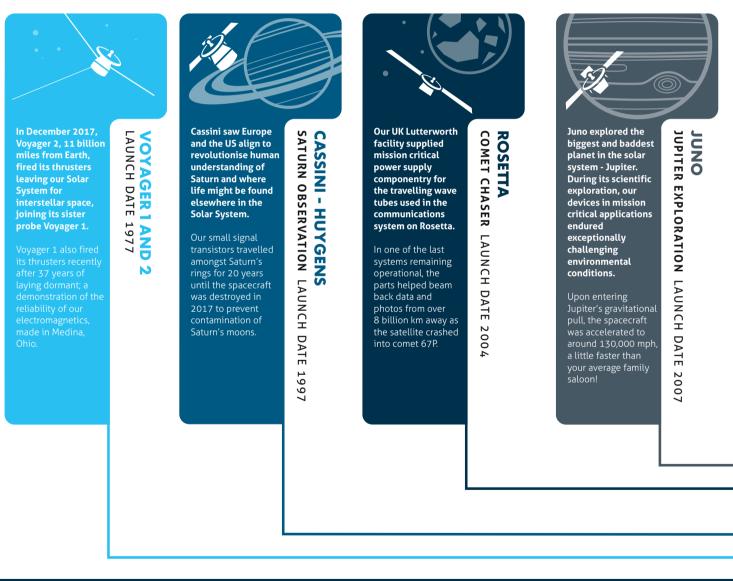
Tackling the challenges of new space flights with traceable, innovative solutions

The New Space Challenge

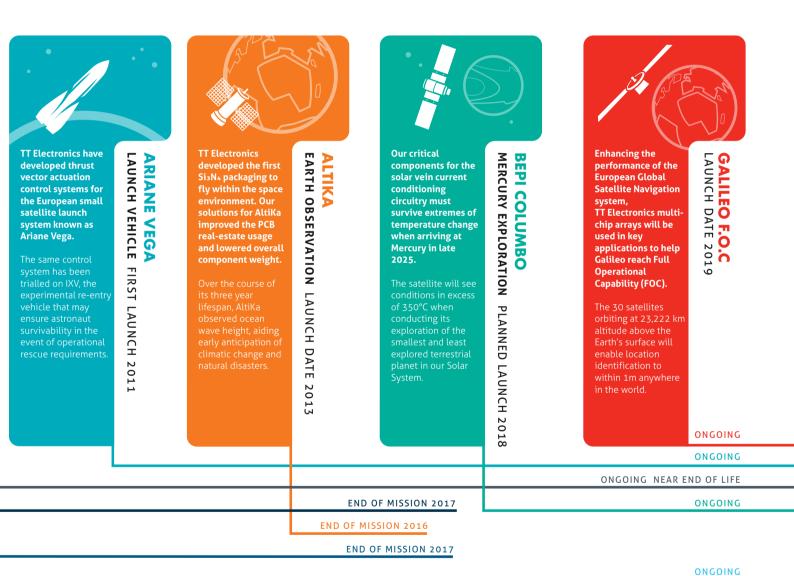
Higher volume satellite constellations in low earth orbit are driving a requirement for increasingly cost effective components. TT's New Space Electronics[®] offer a solution that delivers reduced screening but fully traceable and proven space grade heritage.

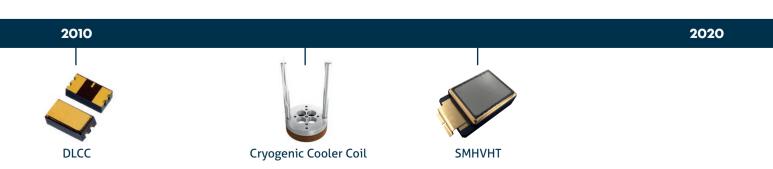


Just some of our notable Missions









Discretes

Readily available packages and die with space heritage. Other options available on request.

Select your package	Select your semiconductor	Select your required screening options
Packages	Semiconductors	Screening Options
	Small signal BJT	Stabilising Bake
LCC1 (UB) (3 or 4 Pad Variant) LCC2 (U)	2N2222A 2N2907A	Pre-Cap Inspection
	2N2369	
	2N5551	High Temperature Reverse Bias
SMT Power Packages LCC4 (U5)	2N5401	High Temperature Gate Bias
	Small Signal Diodes	
	1N4148	Operation Life
	1N6642 BAT54	Temperature Cycling
DLCC2	BZX55XXX	
DLCC3	1FFT-	Acceleration
	JFETs 2N4391	Particle Impact Noise Detection
TO18	2N4392	
	2N4393	Hermetic Seal Testing
T039	2N4416	Residual Gas Analysis
	Power Diodes	
	SiC-1A SiC-2A	Radiography
	SiC-10A	Total Irradiated Dose
	1N5806	
	1N5811 1N5819	Single Event Upset
LCC-20 Pad	102019	Buy-Off Inspection
	Power MOSFETs	
	Si N and P channel up to 50A SiC-1200V 35A	Lot Validation and Group Testing
	SiC-650V 25A	
	Schottky Barrier	

Details of our part number generator for our New Space Electronics® range can be found on our website at: www.ttelectronics.com/new-space-electronics

BYV32 SB30-45

Multi Chip Arrays

Reference Designs

Key Advantages

- PCB real-estate saving
 Lower cost
- Light weight
- Traceable

Full customisation option available

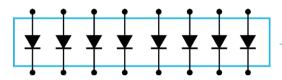
Improved reliability

MCA Reference Designs



Applications

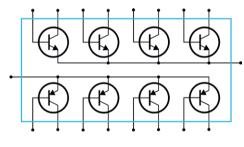
Diode Arrays



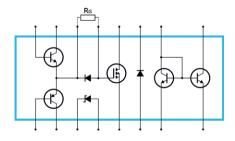


• Dual redundancy

Transistor or MOSFET Arrays



Mixed Technology Arrays



- Individual switches or common junction arrays
- Bridge circuits
- Current multipliers
- High impedance switches
- Voltage rectifiers

- Amplifiers
- Drive circuits
- Protection circuits

Custom Design

Our multi-chip arrays are based on industrial standard leadless chip carriers to provide you, the customer, with the option to fully utilise the package in your required configuration, and with the ability to mix technologies or manufacturers die within the package.

Baseline Screening Options

Our suggested entry point for New Space Electronics[®] discrete semiconductors is shown in NS1 below. The sequence provides an assurance basis with manufacture utilising robust, controlled, space proven processes and designs, including traceability to all materials and operations. NS2 adds baseline mechanical and electrical screening to provide the next level of assurance.

Step	Screen	Condition	NS1	NS2
1	Internal visual inspection ⁵		100%	100%
2	High temperature non- operating life (stabilization bake)	T _{STG} ≤ maximum rated storage temp t = as specified	100%	100%
3	Temperature cycling	5 cycles55°C to +125°C or as specified in maximum ratings		100%
4	Constant acceleration ⁴	Y ₁ direction		100%
5	Serialization		100%	100%
6	Initial electrical test	DC electrical attributes as specified		100%
7	Burn-in ³	Operating or reverse biased as specified. 48 hours (minimum)		100%
8	Final electrical test	DC electrical attributes as specified	100%	100%
9	Hermetic seal ⁴	Fine & Gross Leak Detection		100%
10	External visual examination		100%	100%

New Space Screening requirements 1.2

Notes:

- 1. All screening operations are performed in accordance with MIL-STD-750 or equivalent ESA methods.
- 2. All products can be screened in accordance with the full MIL-STD-19500 or ESA 5000 Generic standard flows contact TT Electronics Sales.
- 3. Conditions for burn-in are set according to the device type and standard operating conditions for ambient or case rated devices.
- 4. Applicable for cavity devices, plastics excluded.
- 5. Internal visual inspection carried out by TT Electronics in accordance with appropriate standard only on cavity devices.



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